



4/17/2012

RELIABILITY MONITOR REPORT  
FOR

**MFN Complementary BiCMOS (CB40)**

**MAXIM Integrated Products**

120 San Gabriel Dr.  
Sunnyvale, CA 94086

This Report was prepared by  
Maxim Reliability Engineering

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX19005CCS+

The calculated failure rate for devices using this process is:

**FAILURE RATE: MTTF (YRS): 1618 QUANTITY: 25 FAILS: 0 FITS: 70.5**

The parameters used to calculate this failure rate are as follows:

**Cf: 60% Ea: 0.7 Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between and .

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**Process Information:**

Process Description: MFN Complementary BiCMOS (CB40)

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**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1140	MAX19005CCS+	135C	334 HRS	25	0	NS6ZCQ002BB
<b>Total:</b>						<b>0</b>	

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